

Microprobes Division Fachverband Mikrosonden (MI)

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Overview of Invited Tutorials, Invited Talks and Sessions

(lecture rooms EW(PN) 202, EMH 225 and TA 201; Poster E)

Invited Tutorials

MI 1.1	Sun	16:00–16:45	EW 202	2D und 3D Röntgenbildgebung mit Synchrotronstrahlung — •TILO BAUMBACH
MI 1.2	Sun	16:45–17:30	EW 202	Hochaufgelöste Röntgenbeugung an niedrigdimensionalen Halbleiterstrukturen — •MICHAEL HANKE
MI 1.3	Sun	17:30–18:15	EW 202	New Lightsources and New Opportunities in Time-resolved Soft X-ray Spectroscopy — •MARTIN BEYE

Invited Talks

MI 2.1	Mon	9:30–10:15	EMH 225	Chemical mapping at the atomic level using energy dispersive X-ray spectroscopy — PETER SCHLOSSMACHER, •BERT FREITAG, DMITRI KLENOV, ADRIAN D ALFONSO, LES ALLEN
MI 2.2	Mon	10:15–11:00	EMH 225	Physical foundations of electron diffraction methods in the scanning electron microscope — •AIMO WINKELMANN
MI 5.1	Wed	9:30–10:15	TA 201	Das Arkanum von Meissener Porzellan: Beharrung oder Wandel? — •CHRISTIAN NEELMEIJER, ULRICH PIETSCH, HEIKE ULBRICHT
MI 5.2	Wed	10:15–11:00	TA 201	From micro to nano - new X-ray techniques as depth sensors for material characterization — •IOANNA MANTOUVALOU, LARS LÜHL, MARCEL PAGELS, WOLFGANG MALZER, BIRGIT KANNGIESSER

Invited talk of the joint session “100 years since the Laue experiment: Topical aspects of diffraction and scattering” (Joint Session KR, BP, DF, MA, MI, MM, GP; related to SYXD)

MI 4.1	Tue	9:30–10:00	EMH 225	The discovery of X-ray interferences, the role of characteristic radiation therein and potential applications of the LAUE method in modern engineering. — •HANS-JÜRGEN ULLRICH, SIEGFRIED DÄBRITZ, ENRICO LANGER, JÜRGEN BAUCH, ANDREAS DANILEWSKY, PETER PAUFLE
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The symposium “100 years of X-ray diffraction: from the Laue-experiment to new frontiers” (SYXD) related to the joint sessions MI 4 and MI 7 takes place on Monday afternoon 15:00–17:30 in H 0105. See SYXD for details of the program.

Sessions

MI 1.1–1.3	Sun	16:00–18:15	EW 202	Innovations in synchrotron X-ray studies
MI 2.1–2.7	Mon	9:30–12:15	EMH 225	TEM- and SEM-based material analysis
MI 3.1–3.4	Mon	12:45–13:45	EMH 225	Scanning probe microscopy
MI 4.1–4.11	Tue	9:30–12:45	EMH 225	100 years since the Laue experiment: Topical aspects of diffraction and scattering (Joint Session KR, BP, DF, GP, MA, MI, MM; related to SYXD)
MI 5.1–5.7	Wed	9:30–12:15	TA 201	X-ray spectrometry and analysis of works of art
MI 6.1–6.8	Wed	12:30–14:30	TA 201	X-ray imaging, holography and tomography
MI 7.1–7.4	Wed	15:00–17:30	Poster E	Poster – 100 years since the Laue experiment: Topical aspects of diffraction and scattering (Joint Session KR, BP, DF, GP, MA, MI, MM; related SYXD)
MI 8.1–8.16	Wed	15:00–17:30	Poster E	Poster – Microanalysis and microscopy

Mitgliederversammlung des Fachverbandes Mikrosonden

Montag 14:00 EMH 225

- Bericht des Fachverbandsvorsitzenden
- Planung der DPG-Tagung 2013
- Verschiedenes